

ATTY. DKT. NO.: 5310-04500

SERIAL NO.: 10/089,588

APPLICANT: Bois et al.

CONFIRMATION NO.: 2551

FILING DATE: July 15, 2002

ART UNIT: 2811

U.S. PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
LP	US01	6475928	11/5/2002	Berenguer et al.			
	US02	6171973	1/9/2001	Schiavone et al.			
	US03	6528341	3/4/2003	Schiavone et al.			
	US04	6215153	4/10/2001	Park			
	US05	5416354	5/16/1995	Blackstone			
	US06	4523213	6/11/1985	Konaka et al.			
	US07	6093592	7/25/2000	Nakabayashi et al.			
	US08	5510645	4/23/1996	Fitch et al.			
	US09	5847439	12/8/1998	Reinberg			
	US10	6064107	5/16/2000	Yeh et al.			
	US11	5595919	1/21/1997	Pan			
	US12	5166765	11/24/1992	Lee et al.			
	US13	4571609	2/18/1986	Hatano			
	US14	5494837	2/27/1996	Subramanian et al.			
	US15	5646058	7/8/1997	Taur et al.			
	US16	5693542	12/2/1997	Suh et al.			
	US17	6037605	3/14/2000	Yoshimura			
	US18	4954871	9/4/1990	Mizutani et al.			
	US19	5834793	11/10/1998	Shibata			
	US20	6091076	7/18/2000	Deleonibus			
	US21	6294812	09/25/01	Ding et al.			
	US22	6667513	12/23/03	Skotnicki et al.			
	US23	6607968	08/19/03	Jurczak et al.			
	US24	6727186	04/27/04	Skotnicki et al.			
	US25	6713356	03/30/04	Skotnicki et al.			
✓	US26	6150241	11/21/2000	Deleonibus			

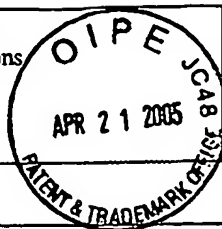
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FOREIGN PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	Translation
LP ↓ ✓	F01	10116988	5/6/1998	JP		Abstract
	F02	6120490	4/28/1994	JP		Abstract
	F03	63278375	11/16/1988	JP		Abstract
	F04	11067682	3/9/1999	JP		Abstract
	F05	9723000	6/26/1997	WO		N/A
	F06	19543859	6/27/1996	DE		US5693542
	F07	63266879	11/2/1988	JP		Abstract
	F08	2750534	1/2/1998	FR		US6150241
	F09	05299647	11/12/1993	JP		Abstract
	F10	60175458	9/9/1985	JP		Abstract
	F11	04251939	9/8/1992	JP		Abstract
	F12	04091481	3/24/1992	JP		Abstract

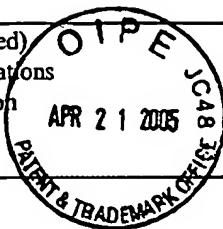
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### OTHER ART

EXAM. INITIALS	REF. DES.	OTHER ART (including Author, Title, Date, Pertinent Pages, etc.)
LP	OA01	"MOS Transistors with Bottom-Isolated Source/Drain Regions", Research Disclosure, GB, Industrial Opportunities LTD., Havant, no. 398, June 1, 1997, pages 378-379, XP000726504; ISSN: 0374-4353.
	OA02	Rapport De Recherche Europeene for EP 00 40 0672, Date d'achevement de la recherche June 23, 2000 (2 pages)./
	OA03	USPTO Office communication for U.S. Patent Application No. 09/522,794 mailed on July 5, 2001 (8 pages).
	OA04	USPTO Office communication for U.S. Patent Application No. 09/522,794 mailed on March 26, 2002 (8 pages).
	OA05	USPTO Office communication for U.S. Patent Application No. 09/522,794 mailed on September 10, 2002 (4 pages).
	OA06	USPTO Office communication for U.S. Patent Application No. 09/522,794 mailed on December 27, 2002 (9 pages).
	OA07	USPTO Office communication for U.S. Patent Application No. 09/522,794 mailed on July 7, 2003 (9 pages).
	OA08	Rapport d'examen preliminaire international for PCT/FR 00/00641, Date d'achevement du present rapport May 22, 2001 (4 pages).
	OA09	USPTO Office Communication for U.S. Patent Application No. 09/937,056 mailed on July 31, 2002 (9 pages).
	OA10	USPTO Office Communication for U.S. Patent Application No. 09/937,056 mailed on April 10, 2003 (9 pages).
	OA11	Bouillon et al., Ref. XP000753808, "Search for the Optimal Channel Architecture for 0.18/0.12 um Bulk CMOS--Experimental Study", International Electron Devices Meeting 1996, Technical Digest IEDM, San Francisco, December 8, 1996, pages 559-562.
	OA12	International Preliminary Examination Report for PCT/FR00/00642, completed on May 22, 2001 (5 pages).
	OA13	USPTO Office Communication for Application. No. 09/937,108 mailed on April 23, 2002 (9 pages).
	OA14	USPTO Office Communication for Application No. 09/937,108 mailed on April 4, 2003 (3 pages).
	OA15	Rapport de Recherche Internationale for PCT/FR 00/02710 mailed on January 3, 2001 (3 pages).
	OA16	Rapport d'Examen Preliminaire International for PCT/FR00/02710, Date d'achevement du present rapport November 29, 2001 (5 pages).
	OA17	Rapport de Recherche Internationale for PCT/FR 00/00641, Date d'expedition du present rapport de recherché internationale May 11, 2000 (4 pages).
	OA18	International Search Report for PCT/FR 00/2710 mailed on January 3, 2001 (6 pages).
	OA19	U.S. Patent Application No. 09/522,794 filed on March 10, 2000.
	OA20	U.S. Patent Application No. 09/937,056 filed on September 19, 2001.
	OA21	U.S. Patent Application No. 09/937,108 filed on September 19, 2001.
	OA22	Rapport de recherché preliminaire for FR 9903468, Date d'achevement de la recherché December 21, 1999 (2 pages).
	OA23	International Search Report for PCT/FR 00/00642 mailed on July 3, 2000 (6 pages).

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